

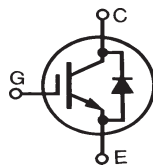
## High Speed IGBT with Diode

**IXSH 30N60B2D1**  
**IXST 30N60B2D1**

$V_{CES} = 600\text{ V}$   
 $I_{C25} = 48\text{ A}$   
 $V_{CE(sat)} = 2.5\text{ V}$

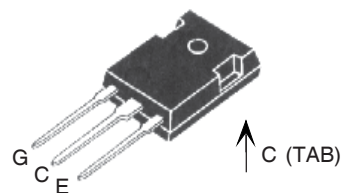
Short Circuit SOA Capability

Preliminary Data Sheet

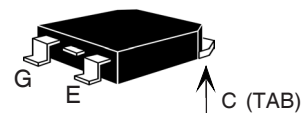


Symbol	Test Conditions	Maximum Ratings	
$V_{CES}$	$T_J = 25^\circ\text{C to } 150^\circ\text{C}$	600	V
$V_{CGR}$	$T_J = 25^\circ\text{C to } 150^\circ\text{C}; R_{GE} = 1\text{ M}\Omega$	600	V
$V_{GES}$	Continuous	$\pm 20$	V
$V_{GEM}$	Transient	$\pm 30$	V
$I_{C25}$	$T_C = 25^\circ\text{C}$	48	A
$I_{C110}$	$T_C = 110^\circ\text{C}$	30	A
$I_{F(110)}$		28	A
$I_{CM}$	$T_C = 25^\circ\text{C}, 1\text{ ms}$	90	A
<b>SSOA (RBSOA)</b>	$V_{GE} = 15\text{ V}, T_J = 125^\circ\text{C}, R_G = 10\Omega$ Clamped inductive load	$I_{CM} = 48$ @ $0.8 V_{CES}$	A
<b><math>t_{SC}</math> (SCSOA)</b>	$V_{GE} = 15\text{ V}, V_{CE} = 360\text{ V}, T_J = 125^\circ\text{C}$ $R_G = 10\Omega$ , non repetitive	10	$\mu\text{s}$
$P_C$	$T_C = 25^\circ\text{C}$	250	W
$T_J$		-55 ... +150	$^\circ\text{C}$
$T_{JM}$		150	$^\circ\text{C}$
$T_{stg}$		-55 ... +150	$^\circ\text{C}$
<b>Weight</b>	TO-247	6	g
	TO-268	5	g
Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s		300	$^\circ\text{C}$
Maximum tab temperature for soldering for 10s		260	$^\circ\text{C}$

TO-247 (IXSH)



TO-268 (IXST)



G = Gate      C = Collector  
E = Emitter    TAB = Collector

### Features

- International standard package
- Guaranteed Short Circuit SOA capability
- Low  $V_{CE(sat)}$ 
  - for low on-state conduction losses
- High current handling capability
- MOS Gate turn-on
  - drive simplicity
- Fast fall time for switching speeds up to 20 kHz

### Applications

- AC motor speed control
- Uninterruptible power supplies (UPS)
- Welding

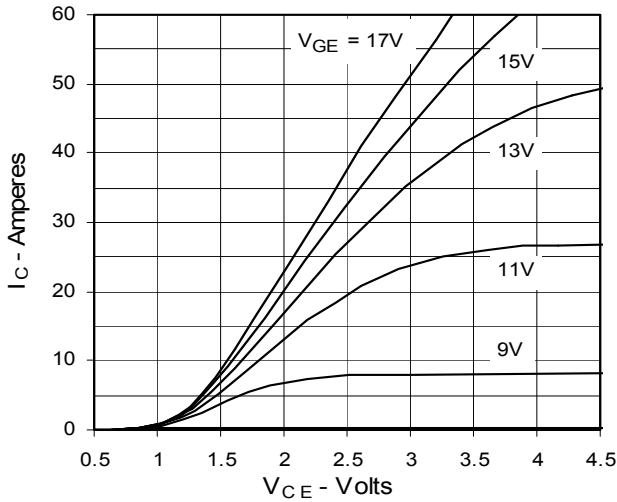
### Advantages

- High power density

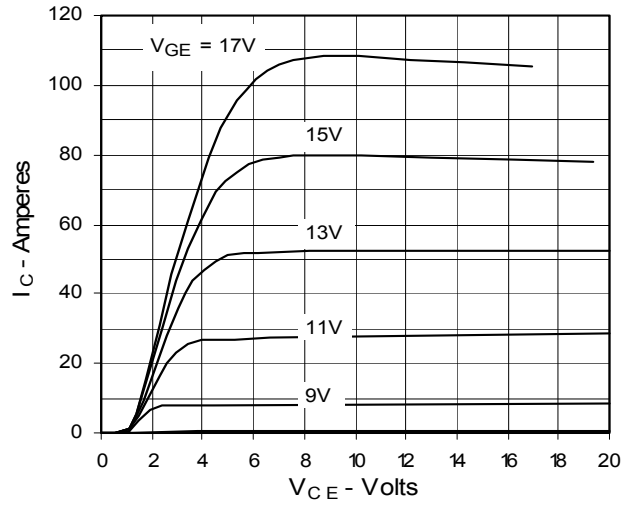
Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		min.	typ.	max.
$V_{GE(th)}$	$I_C = 750\text{ }\mu\text{A}, V_{CE} = V_{GE}$	4.0		7.0 V
$I_{CES}$	$V_{CE} = V_{CES}$ $V_{GE} = 0\text{ V}$			150 $\mu\text{A}$ 1 mA
$I_{GES}$	$V_{CE} = 0\text{ V}, V_{GE} = \pm 20\text{ V}$			$\pm 100\text{ nA}$
$V_{CE(sat)}$	$I_C = 24\text{ A}, V_{GE} = 15\text{ V}$			2.5 V



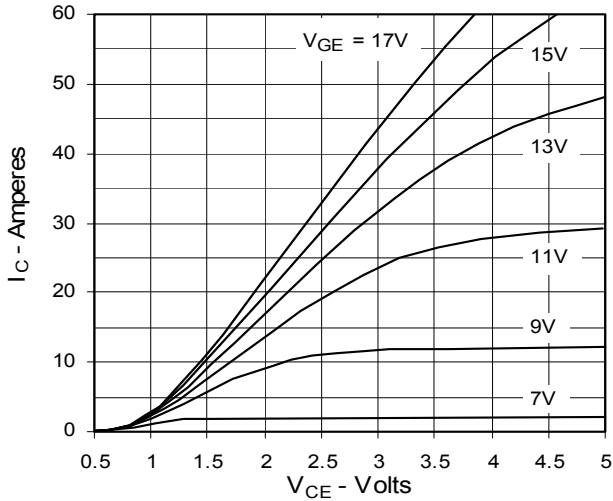
**Fig. 1. Output Characteristics**  
**@ 25 °C**



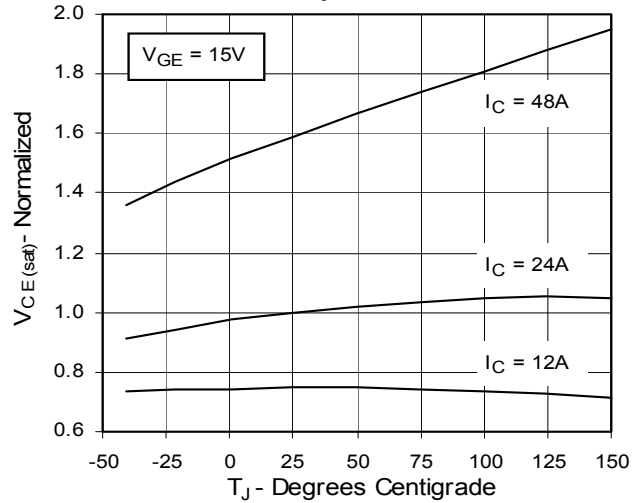
**Fig. 2. Extended Output Characteristics**  
**@ 25 °C**



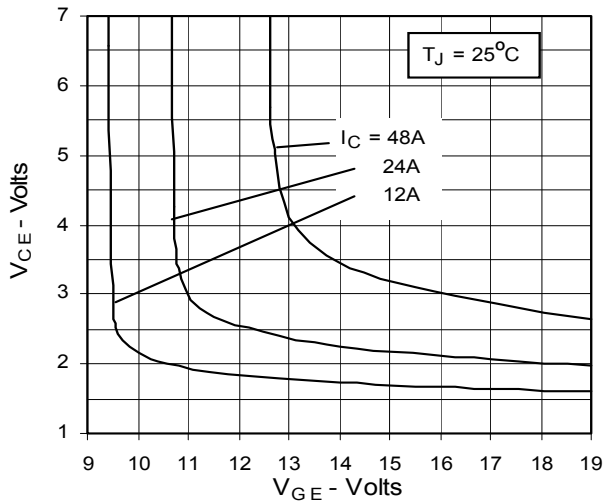
**Fig. 3. Output Characteristics**  
**@ 125 °C**



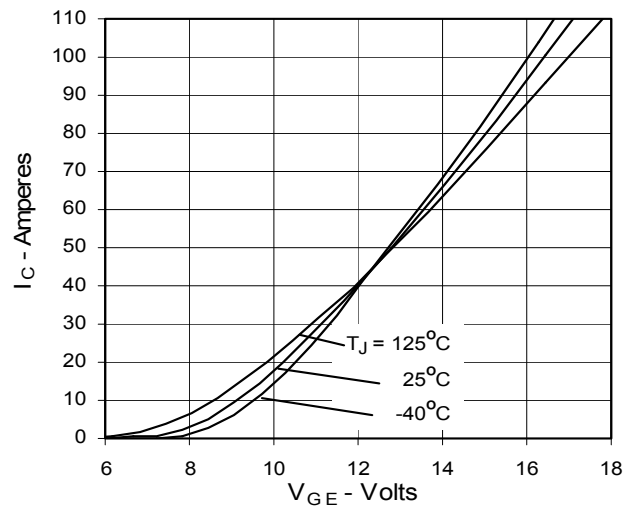
**Fig. 4. Dependence of  $V_{CE(sat)}$  on Temperature**



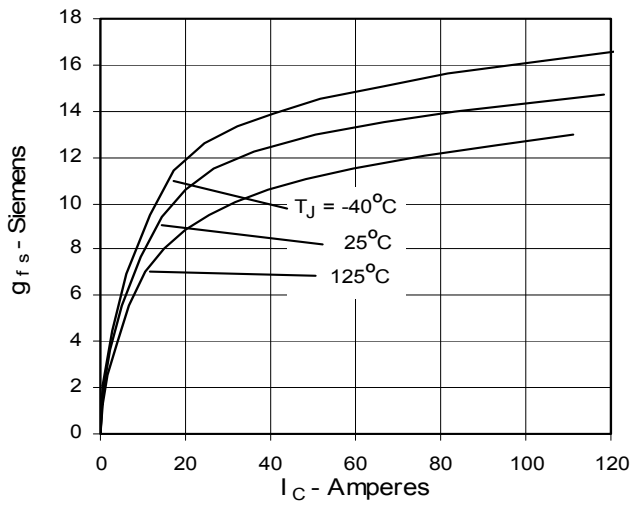
**Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter voltage**



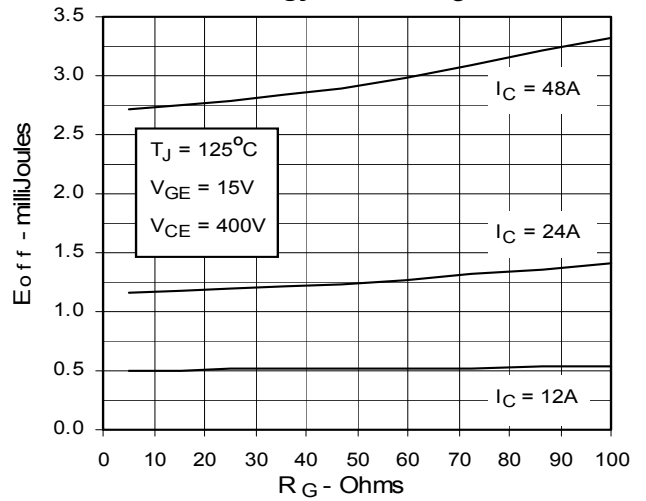
**Fig. 6. Input Admittance**



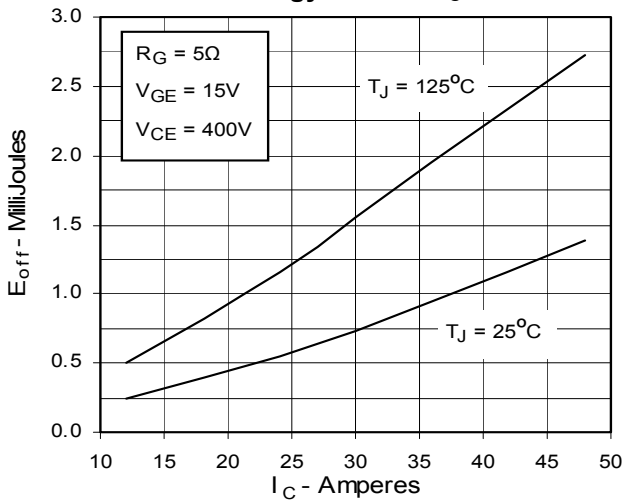
**Fig. 7. Transconductance**



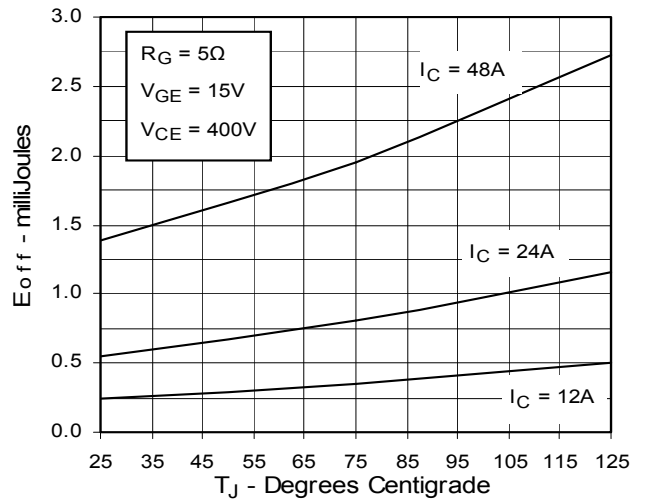
**Fig. 8. Dependence of Turn-off Energy Loss on  $R_G$**



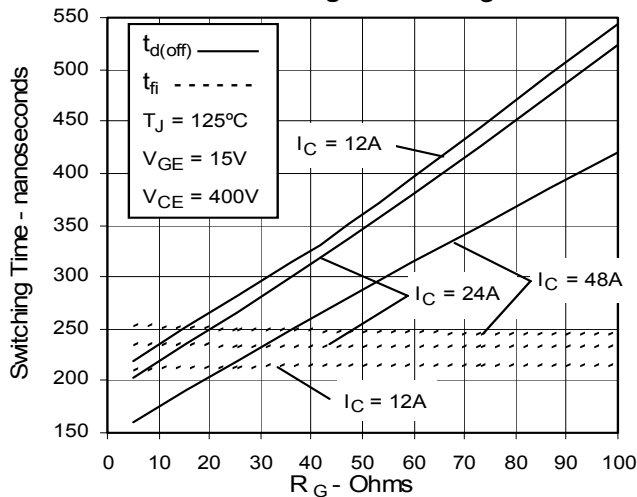
**Fig. 9. Dependence of Turn-Off Energy Loss on  $I_C$**



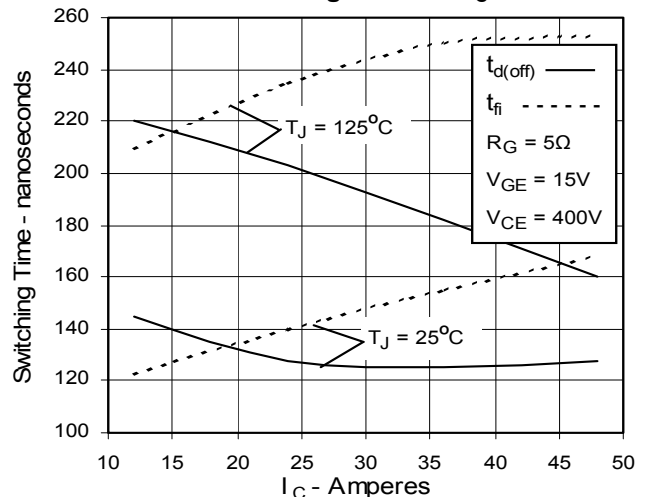
**Fig. 10. Dependence of Turn-off Energy Loss on Temperature**



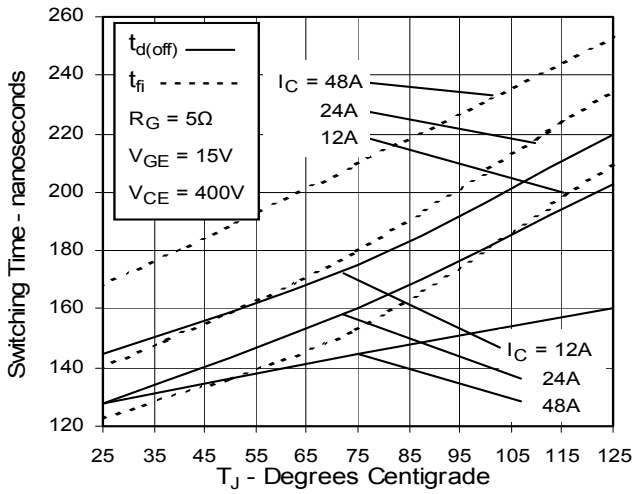
**Fig. 11. Dependence of Turn-off Switching Time on  $R_G$**



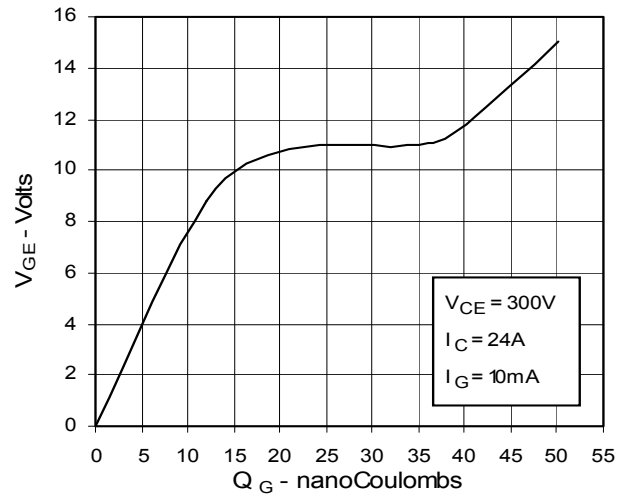
**Fig. 12. Dependence of Turn-off Switching Time on  $I_C$**



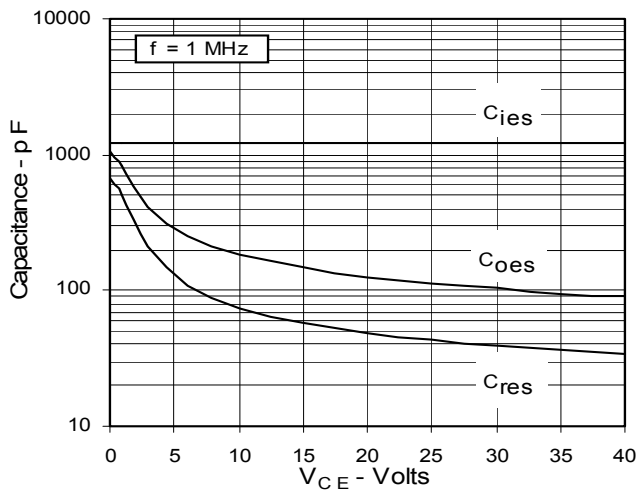
**Fig. 13. Dependence of Turn-off Switching Time on Temperature**



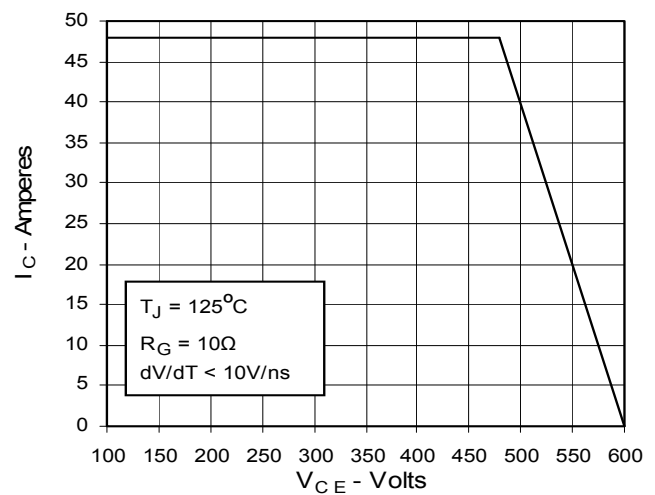
**Fig. 14. Gate Charge**



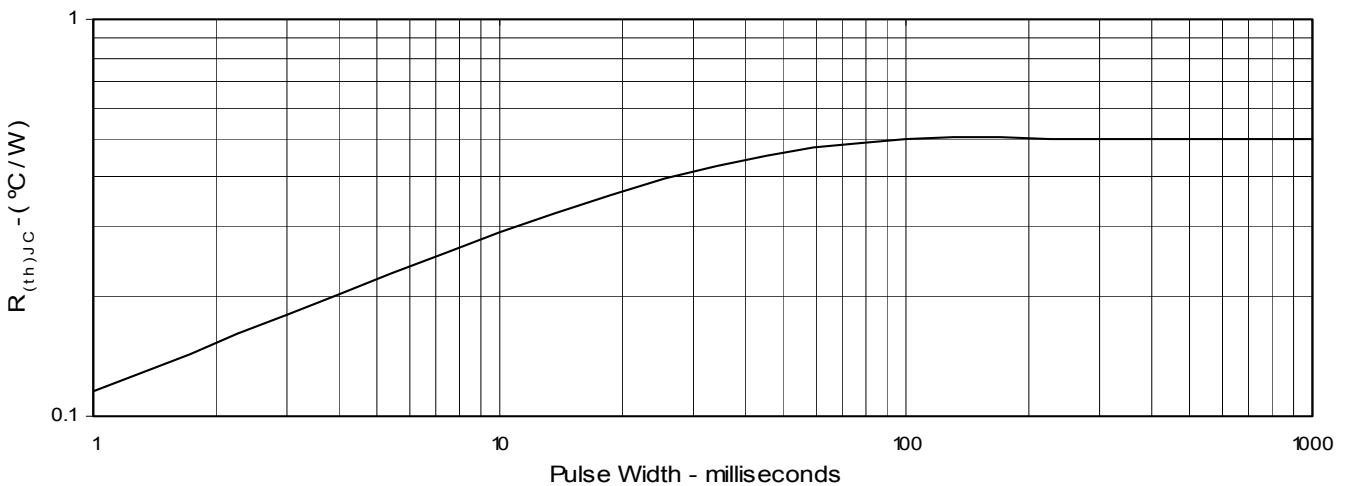
**Fig. 15. Capacitance**

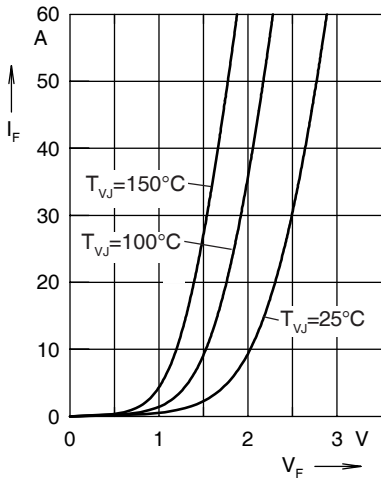


**Fig. 16. Reverse-Bias Safe Operating Area**

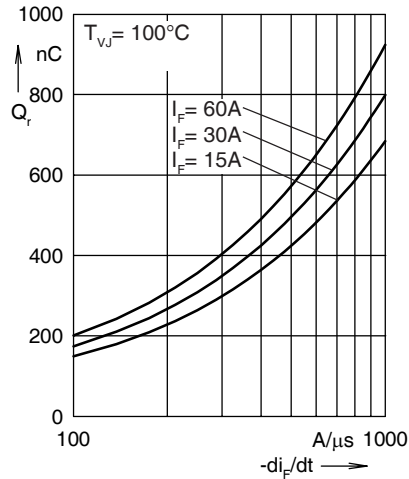


**Fig. 17. Maximum Transient Thermal Resistance**

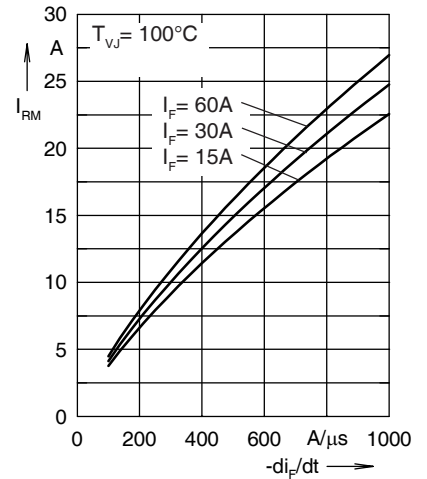




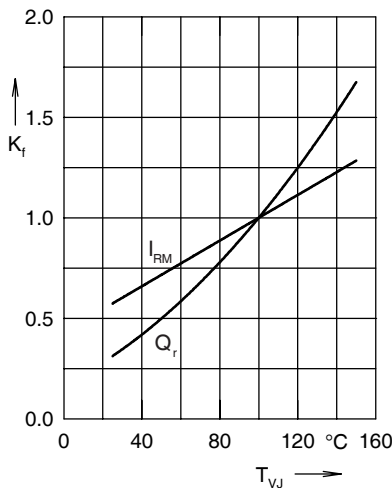
**Fig. 18. Forward current  $I_F$  versus  $V_F$**



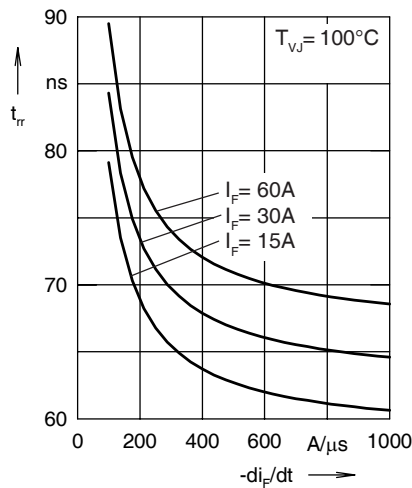
**Fig. 19. Reverse recovery charge**



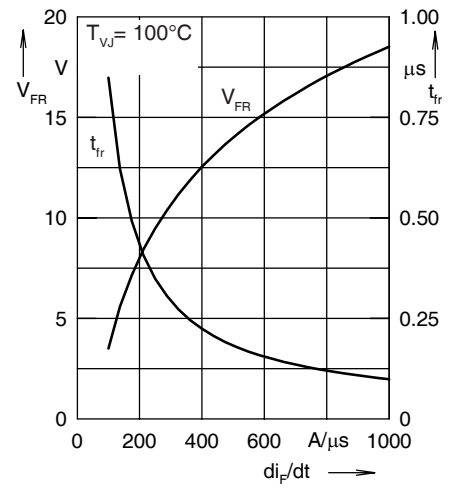
**Fig. 20. Peak reverse current  $I_{RM}$**



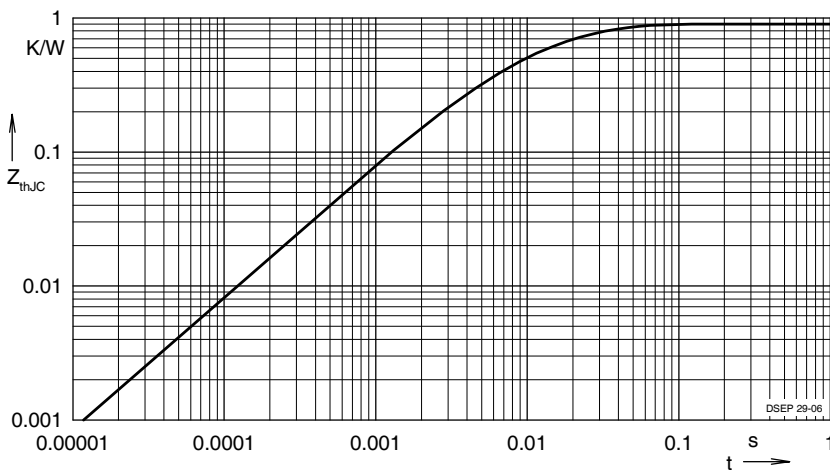
**Fig. 21. Dynamic parameters  $Q_r$ ,  $I_{RM}$**



**Fig. 22. Recovery time  $t_{rr}$  versus**



**Fig. 23. Peak forward voltage  $V_{FR}$**



**Fig. 24. Transient thermal resistance junction to case**

Constants for  $Z_{thjC}$  calculation:

i	$R_{thi}$ (K/W)	$t_i$ (s)
1	0.502	0.0052
2	0.193	0.0003